


<b>Search Notes</b>  	<b>Application/Control No.</b>  10571279	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1626

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
restriction requirement	1-4-2008	sl
stn: registry & caplus	3-18-2008	sl
palm all inventors	3-18-2008	sl
STN: registry & caplus updated	1-2-2008	sl
PALM all inventors updated	1-2-2008	sl
STN registry & caplus updated	7-2-2009	sl
PALM all inventors updated	7-2-2009	sl
STN registry & caplus updated	11-30-2009	sl
PALM all inventors updated	11-30-2009	sl
STN registry & caplus updated	3-3-2010	sl
PALM all inventors updated	3-3-2010	sl
patentability conference. G. Shameem, Y. Chu	3-3-2010	sl

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
548	483	3-3-2010	sl

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